



Electron Devices Society
Santa Clara Valley Chapter

EDS Mini-colloquia on Friday, October 10, 2008

The IEEE Electron Devices Society (EDS) Compact Modeling Technical Committee in collaboration with IEEE Santa Clara Valley (SCV) EDS chapter and IEEE Santa Clara University Student chapter has organized a mini-colloquium on Friday, October 10, 2008. The main focus area of the colloquium is “**New frontiers of compact modeling.**” The invited distinguished speakers and the tentative talks are:

- (1) Prof. M.J. Deen, McMaster University, Canada, *Noise issues in advanced silicon devices and circuits.*
- (2) Prof. M. Miura-Mattausch, Hiroshima University, Japan, *Modeling and characterization of RF/analog and noise using HiSIM2.*
- (3) Prof. J.J. Liou, University of Central Florida, FL, *Compact modeling of silicon controlled rectifier for electrostatic discharge (ESD) computer-aided design applications.*
- (4) Prof. Y. Taur, University of California, San Diego, CA, *Compact modeling of multiple-gate MOSFETs.*
- (5) Prof. L.F. Register, University of Texas, Austin, *Nanoscale MOSFET physics: Observations from non-compact modeling studies.*
- (6) Prof. P.K. Yu, University of California, San Diego, CA, *Wafer bonding for heterogeneous integration.*

Date: FRIDAY, October 10, 2008

Time: 9:00 PM – 5:00 PM

Place: Santa Clara University, Santa Clara, CA

Benson Center, Mission Room

(One-day parking at SCU Campus: \$6.00)

***NO REGISTRATION FEE** (Pre-registration can be sent to Amber Dela Cruz at adelacruz@scu.edu by Tuesday, October 7th, please include your name and affiliation)

For more information, please contact: Samar Saha at samar@ieee.org or Toshishige Yamada at tyamada@scu.edu

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